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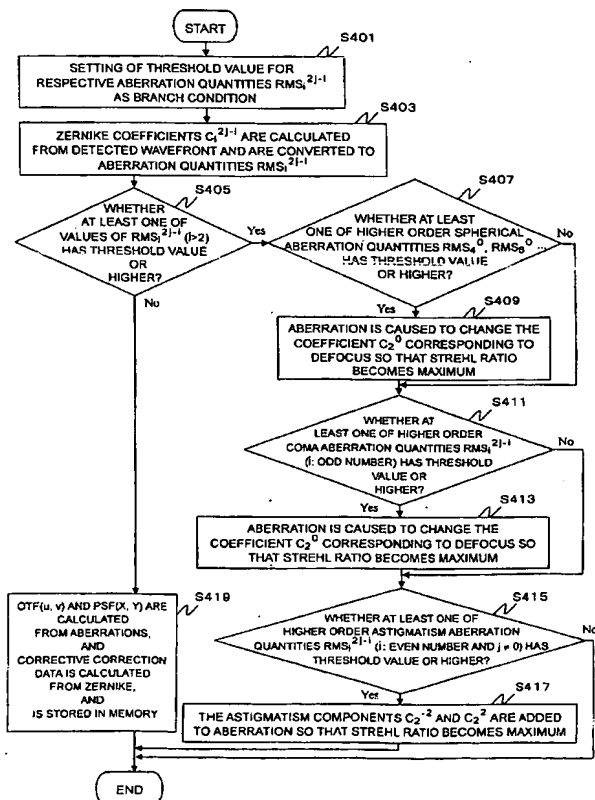
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(54) Title: METHOD AND APPARATUS FOR MEASUREMENT AND CORRECTION OF REFRACTIVE POWER DISTRIBUTION DATA



(57) Abstract: Optical performance in a case where not only higher order aberrations but also lower order aberrations are added, are evaluated, lower order aberration quantities in which for example, a Strehl ratio is large and/or a phase shift is decreased, is calculated, and correction data, such as S, C and A, at that time is obtained, so that a result closer to a subjective value is obtained. An arithmetic part receives measurement data indicating a refractive power distribution of a subject eye and obtains lower order aberrations and higher order aberrations on the basis of the measurement data (S401, S403). The arithmetic part judges whether the higher order aberrations have a specified value or higher (S405). The arithmetic part changes, in a case where the higher order aberrations have the specified values or higher, lower order aberration quantities corresponding to the higher order aberrations having the specified values or higher, obtains appropriate correction data suitable for the subject eye (S407 to S417), and obtains the correction data (S419).